

<b>PCN Number:</b>	20140506000		<b>PCN Date:</b>	05/12/2014							
<b>Title:</b>	Add Cu as Alternative Wire Base Metal for Selected Device(s)										
<b>Customer Contact:</b>	<a href="#">PCN Manager</a>	<b>Phone:</b>	+1(214)480-6037	<b>Dept:</b>	Quality Services						
<b>Proposed 1<sup>st</sup> Ship Date:</b>	08/12/2014	<b>Estimated Sample Availability:</b>	Date provided at sample request								
<b>Change Type:</b>											
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Design	<input type="checkbox"/>	Wafer Bump Site						
<input checked="" type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Data Sheet	<input type="checkbox"/>	Wafer Bump Material						
<input checked="" type="checkbox"/>	Assembly Materials	<input type="checkbox"/>	Part number change	<input type="checkbox"/>	Wafer Bump Process						
<input type="checkbox"/>	Mechanical Specification	<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Wafer Fab Site						
<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process	<input type="checkbox"/>	Wafer Fab Materials						
		<input type="checkbox"/>		<input type="checkbox"/>	Wafer Fab Process						
<b>PCN Details</b>											
<b>Description of Change:</b>											
<p>Texas Instruments is pleased to announce the qualification of Cu as an additional bond wire option for devices listed in "Product affected" section below. Devices will remain in current assembly facility and piece part changes as follows.</p> <table border="1"> <thead> <tr> <th>Material Type</th> <th>Current</th> <th>Proposed</th> </tr> </thead> <tbody> <tr> <td>Wire</td> <td>0.96 mil Au</td> <td>0.8mil Cu</td> </tr> </tbody> </table>						Material Type	Current	Proposed	Wire	0.96 mil Au	0.8mil Cu
Material Type	Current	Proposed									
Wire	0.96 mil Au	0.8mil Cu									
<b>Reason for Change:</b>											
<p>Continuity of supply.</p> <ol style="list-style-type: none"> <li>1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties</li> <li>2) Maximize flexibility within our Assembly/Test production sites.</li> <li>3) Cu is easier to obtain and stock</li> </ol>											
<b>Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):</b>											
None.											
<b>Changes to product identification resulting from this PCN:</b>											
None.											

**Product Affected:**

CC2500RGP	CC2545RGZR	MSP430F5242IRGZR	MSP430F5254IRGCT
CC2500RGPR	CC2545RGZT	MSP430F5242IRGZT	MSP430F5255IRGCR
CC2510F16RHH	FRE004RHBR	MSP430F5244IRGZR	MSP430F5255IRGCT
CC2510F16RHHR	FRE004RHBT	MSP430F5244IRGZT	MSP430F5256IRGCR
CC2510F16RHHT	FRE005RGZR	MSP430F5247IRGCR	MSP430F5256IRGCT
CC2510F32RHH	MSP430F5232IRGZR	MSP430F5247IRGCT	MSP430F5257IRGCR
CC2510F32RHHR	MSP430F5232IRGZT	MSP430F5249IRGCR	MSP430F5257IRGCT
CC2510F32RHHT	MSP430F5234IRGZR	MSP430F5249IRGCT	MSP430F5258IRGCR
CC2510F8RHH	MSP430F5234IRGZT	MSP430F5252IRGCR	MSP430F5258IRGCT
CC2510F8RHHR	MSP430F5237IRGCR	MSP430F5252IRGCT	MSP430F5259IRGCR
CC2510F8RHHT	MSP430F5237IRGCT	MSP430F5253IRGCR	MSP430F5259IRGCT
CC2543RHBR	MSP430F5239IRGCR	MSP430F5253IRGCT	
CC2543RHBT	MSP430F5239IRGCT	MSP430F5254IRGCR	

**Qualification Data**

This qualification has been developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

**Qual Vehicle 1 : CC2533F96RHA (MSL 3-260C)**

## Package Construction Details

Assembly Site:	TI-Clark	Mold Compound:	4208625
# Pins-Designator, Family:	40-RHA, QFN	Mount Compound:	4207123
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.80 Mil Dia., Cu

**Qualification:**  Plan  Test Results

Reliability Test	Conditions	Sample Size/Fail		
		Lot# 1	Lot# 2	Lot# 3
**Temperature Cycle	-55C/+125C (1000 Cyc)	77/0	77/0	77/0
**High Temp Storage Bake	150C (1000 hrs)	77/0	77/0	77/0
**Unbiased HAST	110C/85%RH (264 hrs)	77/0	77/0	77/0
**Biased Temp and Humidity	85C/85%RH (1000 hrs)	26/0	26/0	25/0
ESD - HBM	1500V/1500V	3/0	3/0	3/0
ESD - CDM	500V/500V	3/0	3/0	3/0
Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass

Notes \*\* - Preconditioning sequence: Level 3-260C.

<b>Qual Vehicle 2 : CC1101 RGP (MSL 3-260C)</b>					
Package Construction Details					
Assembly Site:	TI-Clark	Mold Compound:	4208625		
# Pins-Designator, Family:	20-RGP, QFN	Mount Compound:	4207123		
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.80 Mil Dia., Cu		
<b>Qualification:</b> <input type="checkbox"/> Plan <input checked="" type="checkbox"/> <b>Test Results</b>					
Reliability Test	Conditions	Sample Size/Fail			
		Lot# 1	Lot# 2	Lot# 3	
**Temperature Cycle	-55C/+125C (1000 Cyc)	77/0	77/0	77/0	
**High Temp Storage Bake	150C (600 hrs)	77/0	77/0	77/0	
**Unbiased HAST	110C/85%RH (264 hrs)	77/0	77/0	77/0	
**Biased Temp and Humidity	85C/85%RH (1000 hrs)	26/0	26/0	26/0	
ESD - HBM	1500V/1500V	3/0	3/0	3/0	
ESD - CDM	500V/500V	3/0	3/0	3/0	
Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass	
Notes    **- Preconditioning sequence: Level 3-260C.					
<b>Qual Vehicle 3 : CC1260 RGZ (MSL 3-260C)</b>					
Package Construction Details					
Assembly Site:	TI-Clark	Mold Compound:	4208625		
# Pins-Designator, Family:	48-RGZ, QFN	Mount Compound:	4207123		
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.80 Mil Dia., Cu		
<b>Qualification:</b> <input type="checkbox"/> Plan <input checked="" type="checkbox"/> <b>Test Results</b>					
Reliability Test	Conditions	Sample Size/Fail			
		Lot# 1	Lot# 2	Lot# 3	
**Temperature Cycle	-55C/+125C (1000 Cyc)	77/0	77/0	77/0	
**High Temp Storage Bake	150C (1000 hrs)	77/0	77/0	77/0	
**Unbiased HAST	110C/85%RH (264 hrs)	77/0	77/0	77/0	
**Biased Temp and Humidity	85C/85%RH (1000 hrs)	26/0	26/0	26/0	
Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass	
Notes    **- Preconditioning sequence: Level 3-260C.					

<b>Qual Vehicle 4 : MSP430F5528IRGC (MSL 3-260C)</b>				
Package Construction Details				
Assembly Site:	TI-Clark	Mold Compound:	4208625	
# Pins-Designator, Family:	64-RGC, QFN	Mount Compound:	4207123	
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.80 Mil Dia., Cu	
<b>Qualification:</b> <input type="checkbox"/> Plan <input checked="" type="checkbox"/> <b>Test Results</b>				
Reliability Test	Conditions	Sample Size/Fail		
		Lot# 1	Lot# 2	Lot# 3
**Temperature Cycle	-65C/+150C (500 Cyc)	77/0	77/0	77/0
**Autoclave	121C, 2atm (96 hrs)	77/0	77/0	77/0
** High Temp Storage Bake	170C (420 hrs)	77/0	77/0	77/0
Manufacturability (Assembly)	(per mfg. Site specification)	Pass	-	-
Notes    **- Preconditioning sequence: Level 3-260C.				
<b>Qual Vehicle 5 : MSP430F5259IRGC (MSL 3-260C)</b>				
Package Construction Details				
Assembly Site:	TI-Clark	Mold Compound:	4208625	
# Pins-Designator, Family:	64-RGC, QFN	Mount Compound:	4207123	
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	0.80 Mil Dia., Cu	
<b>Qualification:</b> <input type="checkbox"/> Plan <input checked="" type="checkbox"/> <b>Test Results</b>				
Reliability Test	Conditions	Sample Size/Fail		
		Lot# 1	Lot# 2	Lot# 3
**Temperature Cycle	-65C/+150C (500 Cyc)	77/0		
**Autoclave	121C, 2atm (96 hrs)	77/0		
Manufacturability (Assembly)	(per mfg. Site specification)	Pass		
Notes    **- Preconditioning sequence: Level 3-260C.				

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

<b>Location</b>	<b>E-Mail</b>
USA	<a href="mailto:PCNAmericasContact@list.ti.com">PCNAmericasContact@list.ti.com</a>
Europe	<a href="mailto:PCNEuropeContact@list.ti.com">PCNEuropeContact@list.ti.com</a>
Asia Pacific	<a href="mailto:PCNAsiaContact@list.ti.com">PCNAsiaContact@list.ti.com</a>
Japan	<a href="mailto:PCNJapanContact@list.ti.com">PCNJapanContact@list.ti.com</a>